# **MOSFET** - N-Channel, SUPERFET<sup>®</sup> II

800 V, 46 A, 85 m $\Omega$ 

# **FCH085N80**

## **Description**

SuperFET II MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET II MOSFET is very suitable for the switching power applications such as PFC, server/telecom power, FPD TV power, ATX power and industrial power applications.

#### **Features**

- Typ.  $R_{DS(on)} = 67 \text{ m}\Omega$
- $850 \text{ V} @ \text{T}_{\text{J}} = 150^{\circ}\text{C}$
- Ultra Low Gate Charge (Typ. Q<sub>g</sub> = 196 nC)
- Low E<sub>OSS</sub> (Typ. 18 μJ @ 400 V)
- Low Effective Output Capacitance (Typ. C<sub>oss(eff.)</sub> = 568 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

## **Applications**

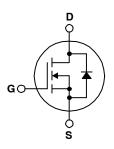
- AC-DC Power Supply
- LED Lighting



# ON Semiconductor®

## www.onsemi.com

V <sub>DS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
800 V	85 mΩ @ 10 V	46 A

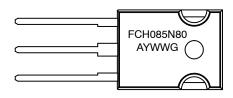


**N-CHANNEL MOSFET** 



TO-247-3LD CASE 340CH

## **MARKING DIAGRAM**



FCH085N80 = Specific Device Code A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 2 of this data sheet.

# ABSOLUTE MAXIMUM RATINGS ( $T_C = 25$ °C unless otherwise noted)

Symbol	Parameter		Value	Unit
$V_{DSS}$	Drain to Source Voltage		800	V
$V_{GSS}$	Gate to Source Voltage	e to Source Voltage - DC		V
		- AC (f > 1 Hz)	±30	
I <sub>D</sub>	Drain Current:	Drain Current: – Continuous ( $T_C = 25^{\circ}C$ )		Α
		- Continuous (T <sub>C</sub> = 100°C)	29	1
I <sub>DM</sub>	Drain Current:	- Pulsed (Note 1)	138	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		1701	mJ
I <sub>AS</sub>	Avalanche Current (Note 2)		9.2	Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		4.4	mJ
dv/dt	MOSFET dv/dt		100	V/ns
	Peak Diode Recovery dv/dt (Note 3)		20	
$P_{D}$	Power Dissipation	(T <sub>C</sub> = 25°C)	446	W
		Derate Above 25°C	3.5	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to + 150	°C
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 seconds		300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 1. Repetitive rating: pulse–width limited by maximum junction temperature. 2.  $I_{AS} = 9.2 \text{ A}$ ,  $V_{DD} = 50 \text{ V}$ ,  $R_{G} = 25 \Omega$ , starting  $T_{J} = 25 ^{\circ}\text{C}$ . 3.  $I_{SD} \le 46 \text{ A}$ ,  $I_{SD} \le 46 \Omega$ ,  $I_{SD} \le 10 \text{ A}$ ,  $I_{SD} \le 10 \text{$ 

## PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
FCH085N80-F155	FCH085N80	TO-247 G03	Tube	N/A	N/A	30 Units

## THERMAL CHARACTERISTICS

Symbol	Parameter	FCH085N80-F155	Unit
R <sub>θJC</sub> Thermal Resistance, Junction to Case, Max.		0.28	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient, Max.	40.0	

# **ELECTRICAL CHARACTERISTICS** ( $T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit
OFF CHARA	ACTERISTICS		-			
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	800	_	-	V
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 1 mA, Referenced to 25°C	-	0.8	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 800 V, V <sub>GS</sub> = 0 V	-	-	25	μΑ
		V <sub>DS</sub> = 640 V, V <sub>GS</sub> = 0 V, T <sub>C</sub> = 125 °C	-	-	250	
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V	-	-	±100	nA
ON CHARA	CTERISTICS	•				
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 4.6 \text{ mA}$	2.5	_	4.5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 23 A	_	67	85	mΩ
9FS	Forward Transconductance	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 23 A	_	55	-	S
DYNAMIC C	HARACTERISTICS	•				
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	8140	10825	pF
C <sub>oss</sub>	Output Capacitance		_	255	340	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		_	10	_	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 480 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	1000	-	pF
C <sub>oss(eff.)</sub>	Effective Output Capacitance	V <sub>DS</sub> = 0 V to 480 V, V <sub>GS</sub> = 0 V	_	728	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10 V	V <sub>DS</sub> = 640 V, I <sub>D</sub> = 46 A, V <sub>GS</sub> = 10 V	-	196	255	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	(Note 4)	-	40	_	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	7	-	72	_	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	0.8	-	Ω
SWITCHING	CHARACTERISTICS	•				
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 400 \text{ V}, I_D = 46 \text{ A},$	-	45	100	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, R_g = 4.7 \Omega$ (Note 4)	-	55	120	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		_	160	330	ns
t <sub>f</sub>	Turn-Off Fall Time		_	35	80	ns
DRAIN-SOU	RCE DIODE CHARACTERISTICS	•				
Is	Maximum Continuous Source to Drain Diode Forward Current		_	_	46	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	138	Α
V <sub>SD</sub>	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 46 A	-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 46 A,	-	800	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	di <sub>F</sub> /dt = 100 A/μs	_	32	-	μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of operating temperature typical characteristics.

## **TYPICAL CHARACTERISTICS**

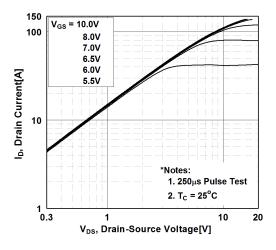


Figure 1. On-Region Characteristics

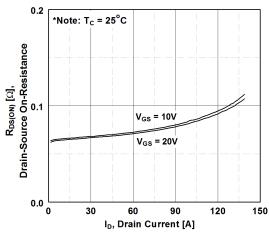


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

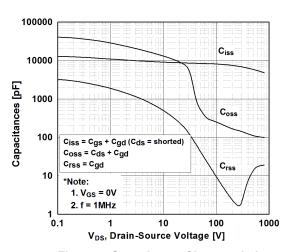


Figure 5. Capacitance Characteristics

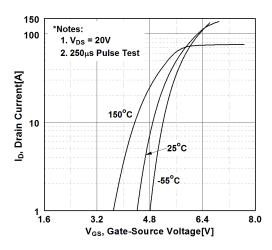


Figure 2. Transfer Characteristics

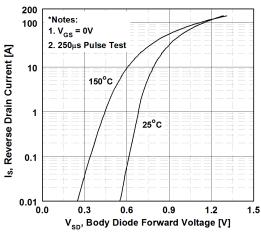


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

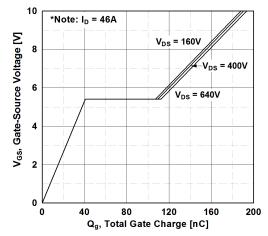


Figure 6. Gate Charge Characteristics

## **TYPICAL CHARACTERISTICS**

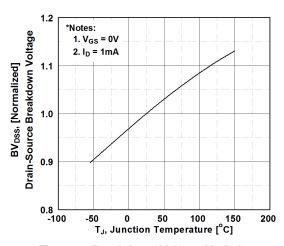


Figure 7. Breakdown Voltage Variation vs. Temperature

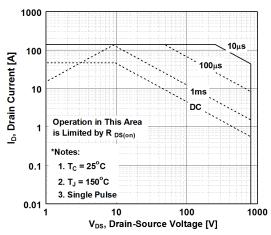


Figure 9. Maximum Safe Operating Area

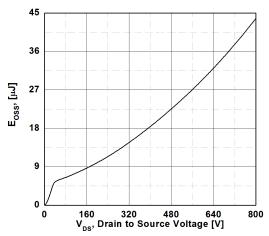


Figure 11. Eoss vs. Drain to Source Voltage

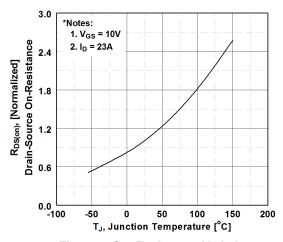


Figure 8. On–Resistance Variation vs.
Temperature

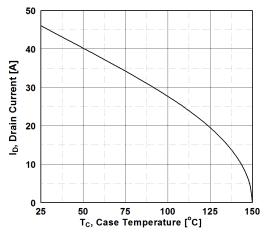


Figure 10. Maximum Drain Current vs. Case Temperature

# **TYPICAL CHARACTERISTICS**

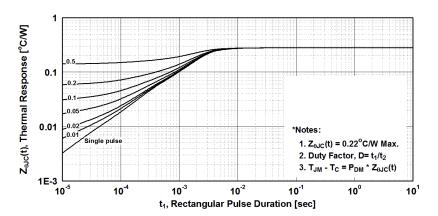


Figure 12. Transient Thermal Response Curve

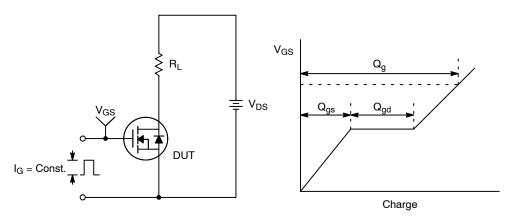


Figure 13. Gate Charge Test Circuit & Waveform

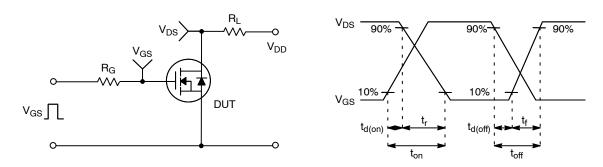


Figure 14. Resistive Switching Test Circuit & Waveforms

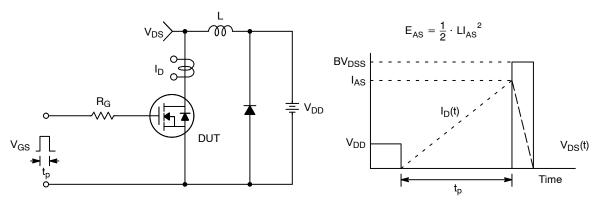


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

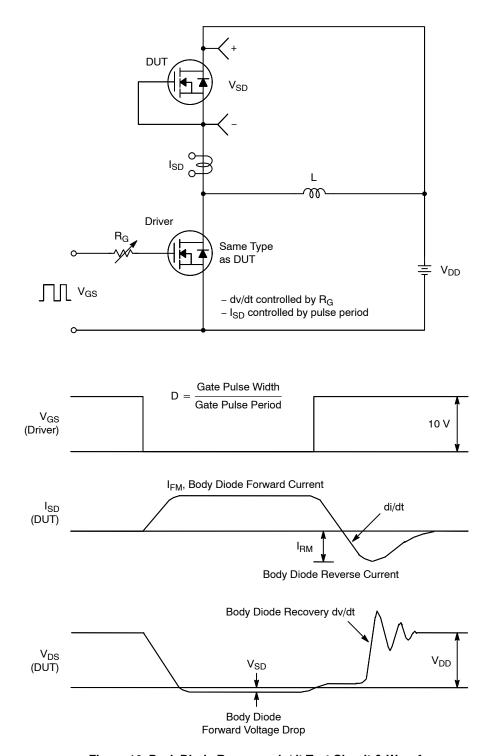
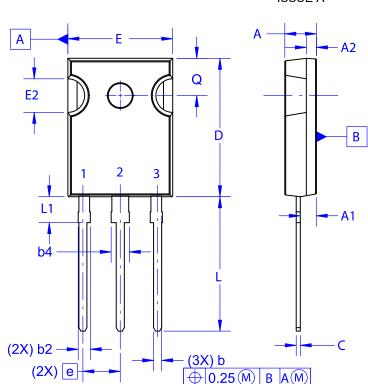


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

SUPERFET is a registered trademark of Semiconductor Components Industries, LLC (SCILLC) or its subsidiaries in the United States and/or other countries.

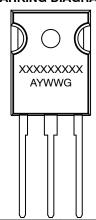
## TO-247-3LD CASE 340CH **ISSUE A**





- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
  D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

# GENERIC **MARKING DIAGRAM\***



XXXX = Specific Device Code

= Assembly Location

WW = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

	DATE	09 OCT 2019
Ø P —		P1 D2
S E1 —	2	D1
		<u>.</u>

DIM	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	4.58	4.70	4.82	
<b>A</b> 1	2.29	2.475	2.66	
A2	1.40	1.50	1.60	
D	20.32	20.57	20.82	
Е	15.37	15.62	15.87	
E2	4.96	5.08	5.20	
е	~	5.56	~	
L	19.75	20.00	20.25	
L1	3.69	3.81	3.93	
ØΡ	3.51	3.58	3.65	
Q	5.34	5.46	5.58	
S	5.34	5.46	5.58	
b	1.17	1.26	1.35	
b2	1.53	1.65	1.77	
b4	2.42	2.54	2.66	
С	0.51	0.61	0.71	
D1	13.08	~	~	
D2	0.51	0.93	1.35	
E1	12.81	~	~	
ØP1	6.61	6.73	6.85	

DOCUMENT NUMBER:	98AON13853G	Electronic versions are uncontrolled except when accessed directly from the Document Reposito Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.	
DESCRIPTION:	TO-247-3LD		PAGE 1 OF 1

ON Semiconductor and un are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

ON Semiconductor and the are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor and see no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and

#### **PUBLICATION ORDERING INFORMATION**

LITERATURE FULFILLMENT:
Email Requests to: orderlit@onsemi.com

ON Semiconductor Website: www.onsemi.com

TECHNICAL SUPPORT North American Technical Support: Voice Mail: 1 800-282-9855 Toll Free USA/Canada Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative